




Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/790,419	LIAO, SUNG YIE	
	Examiner	Art Unit	
	Richale L. Haney	3765	

ISSUE CLASSIFICATION											
ORIGINAL					CROSS REFERENCE(S)						
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
02		172			02	209.11	209.13	209.12	195.1		
INTERNATIONAL CLASSIFICATION											
A	4	2	B	1/06							
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RLH 10/20/2005 (Assistant Examiner) (Date)					 JOHN J. CALVERT SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER, 3700 (Primary Examiner) (Date) 10/25/05					Total Claims Allowed: 4	
 (Legal Instruments Examiner) (Date) 10/28/05										O.G. Print Claim(s) 1	

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47		
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